Application/Control No.	Applicant(s)/Patent under Reexamination
10/688,400	ZHOU ET AL.
Examiner	Art Unit
Joseph Martinez	2873

SEARCHED					
	JLAN	CHED	T		
Class	Subclass	Date	Examiner		
359	265, 273	4/24/2007	JPM		
345	49, 105	4/24/2007	JPM		
348	817	4/24/2007	JPM		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
·	DATE	EXMR		
reviewed related apps via inventor search; re search class/sub and double patenting	4/24/2007	JPM		
see EAST text search attached: 359/245, 247, 252, 253, 265-275; 345/49, 105; 348/817; 546/2	4/24/2007	JPM		
see EAST search attached: USPGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB	4/24/2007	JPM		
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